

**Search Notes**

Application/Control No.

10/681,399

Examiner

Dana Farahani

Applicant(s)/Patent under  
Reexamination

CHEN ET AL.

Art Unit

2891

**SEARCHED**

Class	Subclass	Date	Examiner
438	257	4/27/2005	DF
"	261	4/27/2005	DF
"	265	4/27/2005	DF
"	299	4/27/2005	DF
"	216	4/27/2005	DF
"	591	4/27/2005	DF

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
(physical adj vapor adj deposition) same(anisotropic) same ((collimated adj sputtering) or (long adj throw adj sputtering) or	4/27/2005	DF
memory with gate with (p\$doped or n\$1doped)	4/27/2005	df